

Product data sheet

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- Solid-state silicon-avalanche technology
- Low operating and clamping voltage
- Up to four I/O Lines of Protection
- Ultra low capacitance: 0.3pF typical(I/O to I/O)
- Low Leakage
- Low operating voltage:5V
- Flow-Through design

IEC COMPATIBILITY (EN61000-4)

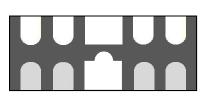
- IEC 61000-4-2 (ESD) ±15kV (air), ±8kV (contact)
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 5A (8/20µs)

Mechanical Characteristics

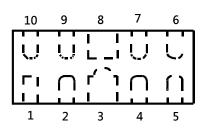
- Molding compound flammability rating: UL 94V-0
- Marking: Marking Code
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

Applications

- Digital Visual Interface(DVI)
- MDDI Ports
- DisplayPortTM Interface
- PCI Express
- High Definition Multi-Media Interface(HDMI)
- eSATA Interfaces



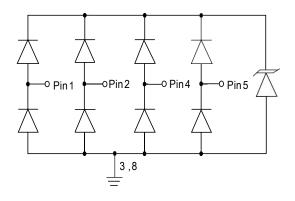
uSON-10



Schematic & PIN Configuration

Pin	Identificaion	
1,2,4,5	Input Lines	
6,7,9,10	Output Lines (No Internal Connection)	
3,8	Ground	

Circuit Diagram



4-Line Protection

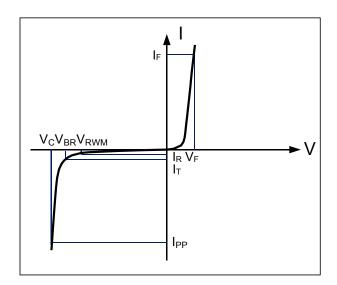


Semiconductor Compiance

Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20µs)	P _{PP}	75	Watts
Peak Pulse Current ($t_p = 8/20 \mu s$)	I _{pp}	5	А
ESD per IEC 61000-4-2(Air) ESD per IEC 61000-4-2(contact)	V _{ESD}	+/-17 +/-12	kV
Operating Temperature	TJ	-55 to + 125	°C
Storage Temperature	T _{STG}	-55 to +150	°C

Electrical Parameters (T=25°C)

Symbol	Parameter			
IPP	Maximum Reverse Peak Pulse Current			
Vc	Clamping Voltage @ IPP			
VRWM	Working Peak Reverse Voltage			
IR	Maximum Reverse Leakage Current @ VRWM			
VBR	Breakdown Voltage @ I⊤			
Ιτ	Test Current			
lF	Forward Current			
VF	Forward Voltage @ I⊧			



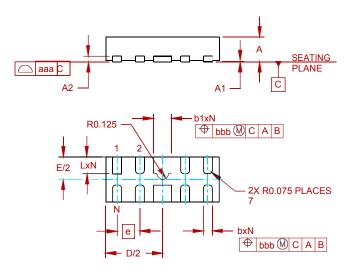
Electrical Characteristics

Parameter	Symbol	Conditions	Minimum	Typical	Maximum	Units
Reverse Stand-Off Voltage	V _{RWM}	Any I/O pin to ground			5V	V
Reverse Breakdown Voltage	V _{BR}	l _t = 1mA Any I/O pin to ground	6.0			V
Reverse Leakage Current	I _R	V _{RWM} = 5V, T=25°C Any I/O pin to ground			1	μA
Clamping Voltage	Vc	l _{pp} =5A, t _p =8/20µs Any I/O pin to ground			15	V
		V _R = 0V, f = 1MHz I/O pin to GND			0.8	pF
Junction Capacitance	Cj	V _R = 0V, f = 1MHz Between I/O pins		0.3		pF





PACKAGE MECHANICAL DATA

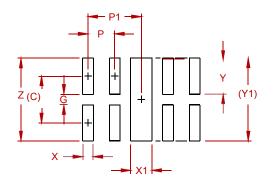


Dimensions in millimeters

A	◄ D►	В

				0110		
DIMENSI ONS						
DIM		MILLIN	MILLIMETERS			
Dim	MIN	NOM	MAX	MIN	NOM	MAX
Α	.020	.023	.026	0.50	0.58	0.65
A1	0.00	.001	.002	0.00	0.03	0.05
A2	(.0	005)		(0	.13)	
b	.006	.008	.010	0.15	0.20	0.25
b1	.014	.016	.018	0.35	0.40	0.45
D	.094	.098	.102	2.40	2.50	2.60
E	.035	.039	.043	0.90	1.00	1.10
е	.020 BSC		0.5	BSC		
L	.012	.015	.017	0.30	0.38	0.425
N	8			8		
aaa	.003		0.08			
bbb	.004		0.10			

Suggested Pad Layout



	DIMENSIONS				
DIM	INCHES	MILLIMETERS			
С	(.034)	(0.875)			
G	.008	0.20			
Р	.020	0.50			
P1	.039	1.00			
Х	.008	0.20			
X1	.016	0.40			
Y	.027	0.675			
Y1	(.061)	(1.55)			
Z	.061	1.55			

NOTES:

CONTROLLING DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES). THIS LAND PATTERN IS FOR REFERENCE PURPOSES ONLY. CONSULT YOUR MANUFACTURING GROUP TO ENSURE YOUR COMPANY'S MANUFACTURING GUIDELINES ARE MET.

REEL SPECIFICATION

P/N	PKG	QTY
AZ1045-04F-MS	DFN2510	3000





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